

Low Cost Sample/Hold Amplifier

AD582

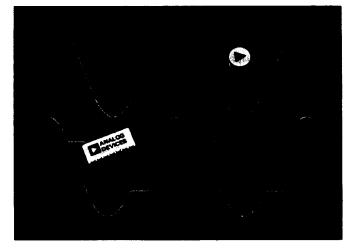
FEATURES

Suitable for 12-Bit Applications High Sample/Hold Current Ratio: 10⁷ Low Acquisition Time: 6µs to 0.1% Low Charge Transfer: <2pC

High Input Impedance in Sample and Hold Modes

Connect in Any Op Amp Configuration

Differential Logic Inputs



PRODUCT DESCRIPTION

The AD582 is a low cost integrated circuit sample and hold amplifier consisting of a high performance operational amplifier, a low leakage analog switch and a JFET integrating amplifier — all fabricated on a single monolithic chip. An external holding capacitor, connected to the device, completes the sample and hold function.

With the analog switch closed, the AD582 functions like a standard op amp; any feedback network may be connected around the device to control gain and frequency response. With the switch open, the capacitor holds the output at its last level, regardless of input voltage.

Typical applications for the AD582 include sampled data systems, D/A deglitchers, analog de-multiplexers, auto null systems, strobed measurement systems and A/D speed enhancement.

The device is available in two versions: the "K" specified for operation over the 0 to +70°C commercial temperature range and the "S" specified over the extended temperature range, -55°C to +125°C. All versions may be obtained in either the hermetic sealed, TO-100 can or the TO-116 DIP.

PRODUCT HIGHLIGHTS

- The specially designed input stage presents a high impedance to the signal source in both sample and hold modes (up to ±12V). Even with signal levels up to ±V_S, no undesirable signal inversion, peaking or loss of hold voltage occurs.
- The AD582 may be connected in any standard op amp configuration to control gain or frequency response and provide signal inversion, etc.
- 3. The AD582 offers a high, sample-to-hold current ratio: 10⁷. The ratio of the available charging current to the holding leakage current is often used as a figure of merit for a sample and hold circuit.
- 4. The AD582 has a typical charge transfer less than 2pC. A low charge transfer produces less offset error and permits the use of smaller hold capacitors for faster signal acquisition.
- 5. The AD582 provides separate analog and digital grounds, thus improving the device's immunity to ground and switching transients

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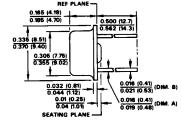
Telex: 174059 Cables: ANALOG NORWOODMASS

SPECIFICATIONS (typical @ +25°C, V_S = ±15V and C_H = 1000pF, A = +1 unless otherwise specified)

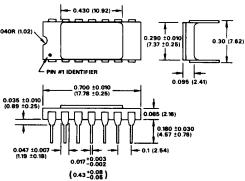
MODEL	AD582K	AD582S	OUTLINE DIMENSIO Dimensions shown in inches an
SAMPLE/HOLD CHARACTERISTICS	-		
Acquisition Time, 10V Step to 0.1%,		_	0.165 (4.19)
C _H = 100pF	бµѕ	•	0.185 (4.70) 0.500 (12.7)
Acquisition Time, 10V Step to 0.01%,	25μs	•	0.335 (8.51)
C _H = 1000pF Aperture Time, 20V p-p Input,	2043		0.370 (9.40)
Hold OV	200ns	•	0.306 (7.76) 0.365 (9.02)
Aperture Jitter, 20V p-p Input,			
Hold 0V	15ns	•	0.032 (0.81)
Settling Time, 20V p-p Input,	0.5μs	•	0.01 (0.25) 0.01
Hold OV, to 0.01%	100pA max	•	0.04 (1.01) 0.0H
Droop Current, Steady State, ±10V _{OUT} Droop Current, T _{min} to T _{max}	1nA	150nA max	SEATING PLANE -
Charge Transfer	5pC max (1.5pC typ)	•	0.115 (2.92)
Sample to Hold Offset	0.5mV	•	0.12 (3.05) 0.16 (4.06) 0.23 (5.84)
Feedthrough Capacitance			
20V p-p, 10kHz Input	0.05pF	*	05 6 7° 0
TRANSFER CHARACTERISTICS			03 2 1 10 99
Open Loop Gain			0.00
$V_{OUT} = 20V p-p, R_L = 2k$	25k min (50k typ)	•	0.028
Common Mode Rejection	40dB m:- /70dB)	•	36.000
V _{CM} = 20V p-p	60dB min (70dB typ)		
Small Signal Gain Bandwidth VOUT = 100mV p-p, CH = 100pF	1.5MHz	•	TO-100 "H"
Full Power Bandwidth			0.430 (10.92)
V _{OUT} = 20V p-p, C _H = 100pF	70kHz	*	-
Slew Rate			0.040R (1.02)
$V_{OUT} = 20V p \cdot p, C_H = 100pF$	3V/μs	*	0.290
Output Resistance		_	
Hold Mode, $I_{OUT} = \pm 5 mA$	12Ω	•	PIN #1 IDENTIFIER
Linearity	±0.01%	*	
V _{OUT} = 20V p-p, R _L = 2k Output Short Circuit Current	±25mA	•	0.700 ±0.010 (17.78 ±0.25)
			0.035 ±0.010 (0.89 ±0.25)
ANALOG INPUT CHARACTERISTICS	6mV max (2mV typ)	•	<u>+</u> \(\)-(\)-(\)-(\)-(\)-(\)-(\)-(\)-(\)-(\)
Offset Voltage Offset Voltage, T _{min} to T _{max}	4mV	8mV max (5mV typ)	
Bias Current	3μA max (1.5μA typ)	•	∪ U U Ü U Ü U <u>U — t`</u>
Offset Current	300nA max (75nA typ)	•	0.047 ±0.007 - - 0.1 (2.5 (1.19 ±0.18)
Offset Current, Tmin to Tmax	100nA	400nA max (100nA typ)	(1.19 ±0.18) 0.017 +0.003 -0.002
Input Capacitance, f = 1MHz	2pF	•	(0.43 ^{+0.08} _{-0.06})
Input Resistance, Sample or Hold	зомΩ	•	TO-116 "D"
20V p-p Input, A = +1	30V	•	
Absolute Max Diff Input Voltage Absolute Max Input Voltage, Either Input	±V _S	•	PIN CONFIGURAT
			TOP VIEW
DIGITAL INPUT CHARACTERISTICS			LOGIC
+Logic Input Voltage Hold Mode, T _{min} to T _{max} , -Logic @ 0V	+2V min	•	[
Sample Mode, T _{min} to T _{max} , -Logic @ 0V	+0.8V max	•	LOGIC 110
+Logic Input Current			^{IN+} (1)————————————————————————————————————
Hold Mode, +Logic @ +5V, -Logic @ 0V	1.5μΑ	*	<i>~</i> ₼ ~
Sample Mode, +Logic @ 0V, -Logic @ 0V	1nA	•	+ IN ~ Y
-Logic Input Current	244		
Hold Mode, +Logic @ +5V, -Logic @ 0V	24μΑ 4μΑ	*	\¬ <u>・</u> <u>・</u> ・ <u>・</u> ・
Sample Mode, +Logic @ 0V, -Logic @ 0V Absolute Max Diff Input Voltage, +L to -L	4μΑ +15V/-6V	•	
Absolute Max Input Voltage, Either Input	±V _S	•	3-1
			. NULL J
POWER SUPPLY CHARACTERISTICS	+037 +1037	±9V to ±22V	
Operating Voltage Range	±9V to ±18V 4.5mA max (3mA typ)	±77 (O ±227	NULL
Supply Current, R _L = ∞	T.JIIIA MAX (JIIIA 199)		_v.
Power Supply Rejection, $\Delta V_S = 5V$, Sample Mode (see next page)	60dB min (75dB typ)	•	10 DIN TO 100
			. 10 PIN TO-100
TEMPERATURE RANGE	0 to +70°C	-55°C to +125°C	LOGIC LOGIC NC NC IN+ IN- +Vs
Specified Performance Operating	-25°C to +85°C	-55°C to +125°C	13 - 12 - 11 - 10 -
Storage	-65°C to +150°C	•	
Lead Temperature (Soldering, 15 sec)	+300°C	•	I

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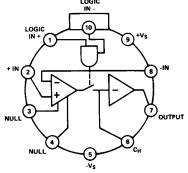
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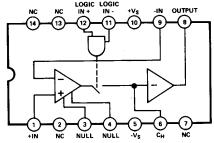






TIONS





14 PIN DIP TO-116

^{*}Specifications same as AD582K.

Specifications subject to change without notice.

Applying the AD582

APPLYING THE AD582

Both the inverting and non-inverting inputs are brought out to allow op amp type versatility in connecting and using the AD582. Figure 1 shows the basic non-inverting unity gain connection requiring only an external hold capacitor and the usual power supply bypass capacitors. An offset null pot can be added for more critical applications.

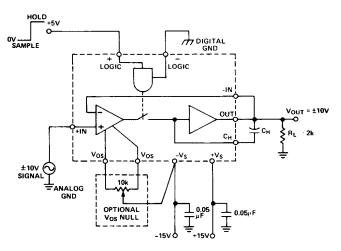


Figure 1. Sample and Hold with A = +1

Figure 2 shows a non-inverting configuration where voltage gain, A_V , is set by a pair of external resistors. Frequency shaping or non-linear networks can also be used for special applications.

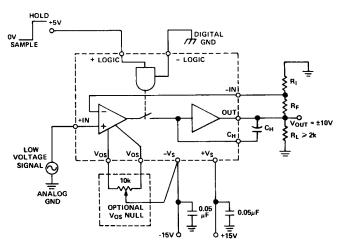


Figure 2. Sample and Hold with $A = (1 + R_F/R_I)$

The hold capacitor, C_H, should be a high quality polystyrene (for temperatures below +85°C) or Teflon type with low dielectric absorption. For high speed, limited accuracy applications, capacitors as small as 100pF may be used. Larger values are required for accuracies of 12 bits and above in order to minimize feedthrough, sample to hold offset and droop errors (see Figure 6). Care should be taken in the circuit layout to minimize coupling between the hold capacitor and the digital or signal inputs.

In the hold mode, the output voltage will follow any change in the ${}^{-}V_S$ supply. Consequently, this supply should be well regulated and filtered.

Biasing the +Logic Input anywhere between -6V to +0.8V with respect to the -Logic will set the sample mode. The hold mode will result from any bias between +2.0V and (+ V_S - 3V). The sample and hold modes will be controlled differentially with the absolute voltage at either logic input ranging from - V_S to within 3V of + V_S (V_S - 3V). Figure 3 illustrates some examples of the flexibility of this feature.

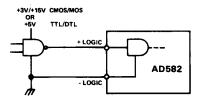


Figure 3A. Standard Logic Connection

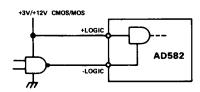


Figure 3B. Inverted Logic Sense Connection

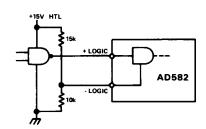


Figure 3C. High Threshold Logic Connection

DEFINITION OF TERMS

Figure 4 illustrates various dynamic characteristics of the AD582.

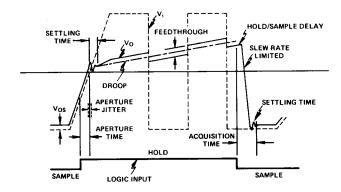


Figure 4. Pictorial Showing Various S/H Characteristics

Aperture Time is the time required after the "hold" command until the switch is fully open and produces a delay in the effective sample timing. Figure 5 is a plot giving the maximum frequency at which the AD582 can sample an input with a given accuracy (lower curve).

Aperture Jitter is the uncertainty in Aperture Time. If the Aperture Time is "tuned out" by advancing the sample-to-hold command 200ns with respect to the input signal, the Aperture Jitter now determines the maximum sampling frequency (upper curve of Figure 5).

Acquisition Time is the time required by the device to reach its final value within a given error band after the sample command has been given. This includes switch delay time, slewing time and settling time for a given output voltage change.

Droop is the change in the output voltage from the "held" value as a result of device leakage. In the AD582, droop can be in either the positive or negative direction. Droop rate may be calculated from droop current using the following formula:

$$\frac{\Delta V}{\Delta T} (Volts/sec) = \frac{I(pA)}{C_H(pF)}$$

(See also Figure 6.)

Feedthrough is that component of the output which follows the input signal after the switch is open. As a percentage of the input, feedthrough is determined as the ratio of the feedthrough capacitance to the hold capacitance (C_F/C_H) .

Charge Transfer is the charge transferred to the holding capacitor from the interelectrode capacitance of the switch when the unit is switched to the hold mode. The charge transfer generates a sample-to-hold offset where:

S/H Offset (V) =
$$\frac{\text{Charge (pC)}}{\text{C}_{\text{H}}(\text{pF})}$$

(See also Figure 6.)

Sample-to-Hold Offset is that component of D.C. offset independent of C_H (see Figure 6). This offset may be nulled using a null pot, however, the offset will then appear during the sampling mode.

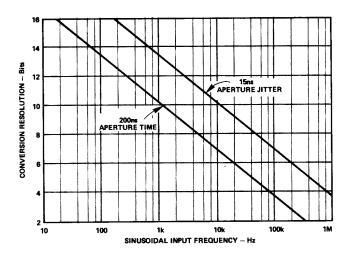


Figure 5. Maximum Frequency of Input Signal for %LSB Sampling Accuracy

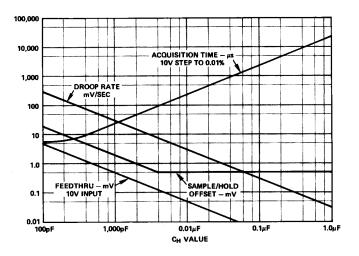


Figure 6. Sample-and-Hold Performance as a Function of Hold Capacitance

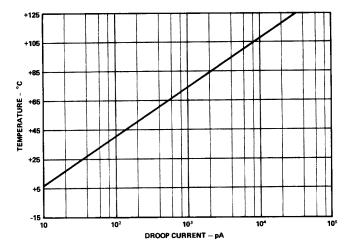


Figure 7. Droop Current vs. Temperature